

Military Bipolar Memory Products

Product Specification

DESCRIPTION

The 82S23 and 82S123 are field-programmable, which means that custom patterns are immediately available by following the Signetics Generic I fusing procedure. The 82S23 and 82S123 devices are supplied with all outputs at a logical Low. Outputs are programmed to a logic High level at any specified address by fusing a Ni-Cr link matrix.

These devices include on-chip decoding and 1 chip enable input for memory expansion. They feature either Open collector or 3-State outputs for optimization of word expansion in bused organizations.

FEATURES

- Address access time: 50ns max
- Input loading: $-150\mu\text{A}$ max
- On-chip address decoding
- One chip enable input
- Output options:
 - 82S23: Open collector
 - 82S123: 3-State
- No separate fusing pins
- Unprogrammed outputs are Low level
- Fully TTL compatible

APPLICATIONS

- Prototyping/volume production
- Sequential controllers
- Format conversion
- Hardwired algorithms
- Random logic
- Code conversion

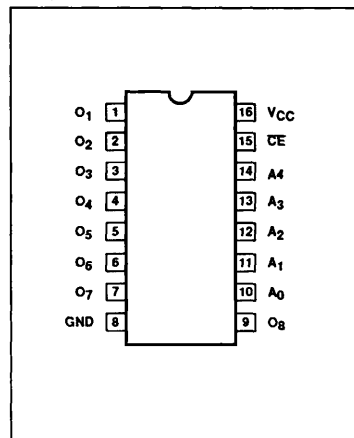
ORDERING INFORMATION

DESCRIPTION	ORDER CODE
16-Pin Ceramic Dual-In-Line 300mil-wide	82S23/BEA, 82S123/BEA
16-Pin Ceramic FlatPack	82S23/BFA, 82S123/BFA

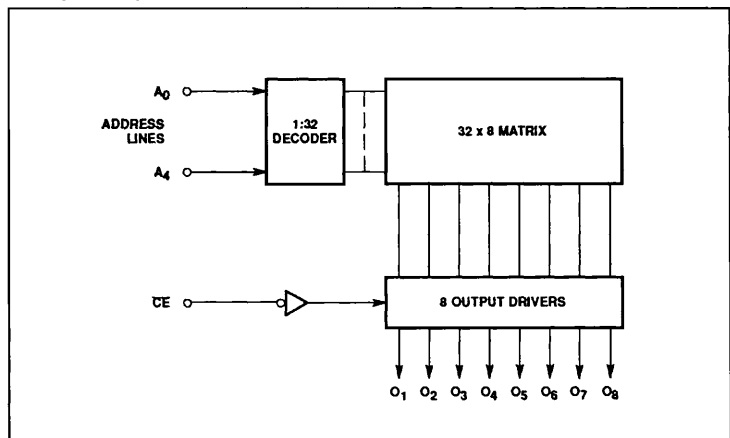
ABSOLUTE MAXIMUM RATINGS

SYMBOL	PARAMETER	RATING	UNIT
V_{CC}	Supply voltage	+7	V_{DC}
V_I	Input voltage	+5.5	V_{DC}
V_O	Output voltage High (82S23)	+5.5	V_{DC}
V_O	Output voltage Off-State (82S123)	+5.5	V_{DC}
T_A	Operating temperature range	-55 to +125	$^{\circ}\text{C}$
T_{STG}	Storage temperature range	-65 to +150	$^{\circ}\text{C}$

PIN CONFIGURATION



BLOCK DIAGRAM



256-Bit TTL Bipolar PROM (32 × 8)

82S23, 82S123

DC ELECTRICAL CHARACTERISTICS $-55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$, $4.5\text{V} \leq V_{\text{CC}} \leq 5.5\text{V}$

SYMBOL	PARAMETER	TEST CONDITIONS ^{1,2}	LIMITS			UNIT
			Min	Typ ⁵	Max	
Input voltage						
V_{IL} V_{IH} V_{IK}	Low High Clamp	$V_{\text{CC}} = 4.5\text{V}$, $I_{\text{I}} = -18\text{mA}$	2.0		0.8 -1.2	V V V
Output voltage						
V_{OL} V_{OH}	Low High	$\overline{\text{CE}} = \text{Low}$ $I_{\text{O}} = 16\text{mA}$ $I_{\text{O}} = -2\text{mA}$, $V_{\text{CC}} = 4.5\text{V}$	2.4		0.5	V V
Input current						
I_{IL} I_{IH1} I_{IH2}	Low High High	$V_{\text{CC}} = 5.5\text{V}$ $V_{\text{I}} = 0.45\text{V}$ $V_{\text{I}} = 2.7\text{V}$ $V_{\text{I}} = 5.5\text{V}$			-150 25 40	μA μA μA
Output current¹						
I_{OLK} I_{OZ} I_{OS}	Leakage (82S23) Hi-Z state (82S123) Short circuit (82S123) ³	$V_{\text{CC}} = 5.5\text{V}$ $\overline{\text{CE}} = \text{High}$, $V_{\text{O}} = 5.5\text{V}$ $\overline{\text{CE}} = \text{High}$, $V_{\text{O}} = 5.5\text{V}$ $\overline{\text{CE}} = \text{High}$, $V_{\text{O}} = 0.4\text{V}$ $V_{\text{CC}} = 5.5\text{V}$, $\overline{\text{CE}} = \text{Low}$, $V_{\text{O}} = 0\text{V}$, High stored	-20		40 40 -40 -100	μA μA μA mA
Supply current						
I_{CC}		$V_{\text{CC}} = 5.5\text{V}$, $\overline{\text{CE}} = \text{High}$			110	mA
Capacitance⁶						
C_{IN} C_{OUT}	Input Output	$\overline{\text{CE}} = \text{High}$, $V_{\text{CC}} = 5.0\text{V}$ $V_{\text{I}} = 2.0\text{V}$ $V_{\text{O}} = 2.0\text{V}$			5 8 10 13	pF pF

AC ELECTRICAL CHARACTERISTICS $-55^{\circ}\text{C} \leq T_A \leq +125^{\circ}\text{C}$, $4.5\text{V} \leq V_{\text{CC}} \leq 5.5\text{V}$

SYMBOL	PARAMETER	TO	FROM	LIMITS			UNIT
				Min	Typ ⁵	Max	
t_{AA}	Access time ⁴	Output	Address		45	50	ns
t_{CE}	Access time ⁴	Output	Chip Enable			30	ns
t_{CD}	Disable time	Output	Chip Disable			30	ns

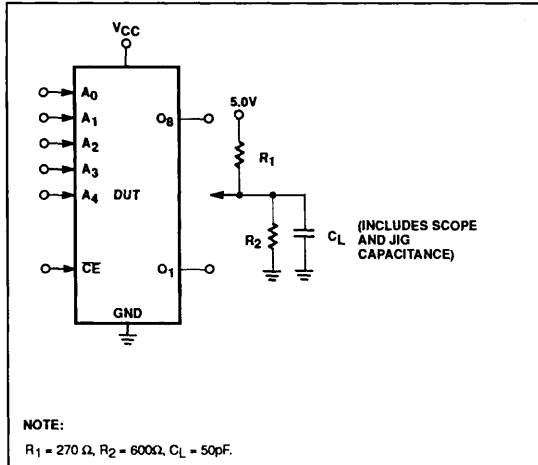
NOTES:

1. Positive current is defined as into the terminal referenced.
2. All voltages with respect to network ground.
3. Duration of short circuit should not exceed 1 second.
4. Tested at an address cycle time of 1 μs .
5. Typical values are at $V_{\text{CC}} = 5\text{V}$, $T_A = +25^{\circ}\text{C}$.
6. Guaranteed but not tested.

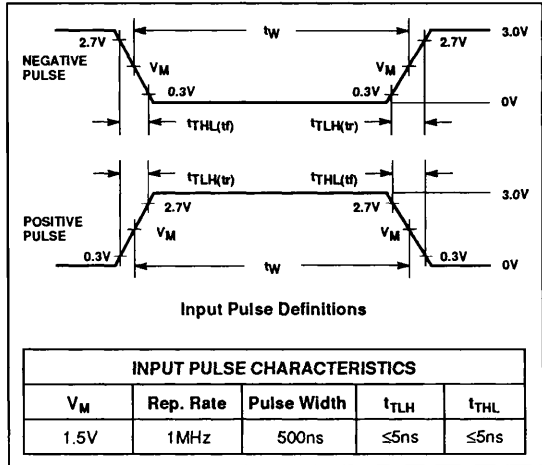
256-Bit TTL Bipolar PROM (32 × 8)

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TEST LOAD CIRCUITS



VOLTAGE WAVEFORMS



TIMING DIAGRAMS

